freescale
飞思卡尔(深圳)功率半导体有限公司

AO7417

P-Channel Enhancement Mode Field Effect Transistor

General Description

The AO7417/L uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 1.5V, in the small SOT363 footprint. This device is suitable for use in buck convertor. *AO7417 and AO7417L are electrically identical.*

-RoHS Compliant

-AO7417L is Halogen Free

Features

V_{DS} (V) = -20V

I_D = -2 A (V_{GS} = -4.5V)

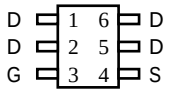
$R_{DS(ON)}$ < 80mΩ (V_{GS} = -4.5V)

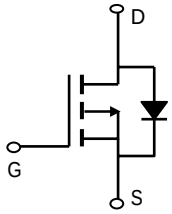
$R_{DS(ON)}$ < 100mΩ (V_{GS} = -2.5V)

$R_{DS(ON)}$ < 125mΩ (V_{GS} = -1.8V)

$R_{DS(ON)}$ < 150mΩ (V_{GS} = -1.5V)

SC-70-6
(SOT-363)
Top View





Absolute Maximum Ratings T_A=25°C unless otherwise noted					
Parameter		**Symbol**	**10 Sec**	**Steady State**	**Units**
Drain-Source Voltage		V_{DS}	-20		V
Gate-Source Voltage		V_{GS}	±8		V
Continuous Drain Current [A]	T_A=25°C	I_D	-2	-1.9	A
	T_A=70°C		-1.7	-1.6	
Pulsed Drain Current [B]		I_{DM}	-20		
Power Dissipation [A]	T_A=25°C	P_D	0.63	0.57	W
	T_A=70°C		0.4	0.36	
Junction and Storage Temperature Range		T_J, T_{STG}	-55 to 150		°C

Thermal Characteristics					
Parameter		**Symbol**	**Typ**	**Max**	**Units**
Maximum Junction-to-Ambient [A]	t ≤ 10s	$R_{\theta JA}$	160	200	°C/W
Maximum Junction-to-Ambient [A]	Steady-State		180	220	°C/W
Maximum Junction-to-Lead [C]	Steady-State	$R_{\theta JL}$	130	160	°C/W

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Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	I_D=-250µA, V_{GS}=0V	-20			V
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS}=-20V, V_{GS}=0V			-1	µA
		T_J=55°C			-5	
I_{GSS}	Gate-Body leakage current	V_{DS}=0V, V_{GS}=±8V			±100	nA
$V_{GS(th)}$	Gate Threshold Voltage	V_{DS}=V_{GS} I_D=-250µA	-0.5	-0.65	-1	V
$I_{D(ON)}$	On state drain current	V_{GS}=-4.5V, V_{DS}=-5V	-20			A
$R_{DS(ON)}$	Static Drain-Source On-Resistance	V_{GS}=-4.5V, I_D=-2A		65	80	mΩ
		T_J=125°C		90	110	
		V_{GS}=-2.5V, I_D=-1.8A		80	100	mΩ
		V_{GS}=-1.8V, I_D=-1.5A		100	125	mΩ
		V_{GS}=-1.5V, I_D=-0.5A		115	150	mΩ
g_{FS}	Forward Transconductance	V_{DS}=-5V, I_D=-2A		10		S
V_{SD}	Diode Forward Voltage	I_S=-1A,V_{GS}=0V		-0.7	-1	V
I_S	Maximum Body-Diode Continuous Current				-1	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	V_{GS}=0V, V_{DS}=-10V, f=1MHz		560	745	pF
C_{oss}	Output Capacitance			80		pF
C_{rss}	Reverse Transfer Capacitance			70		pF
R_g	Gate resistance	V_{GS}=0V, V_{DS}=0V, f=1MHz		15	23	Ω
SWITCHING PARAMETERS						
Q_g	Total Gate Charge	V_{GS}=-4.5V, V_{DS}=-10V, I_D=-2A		8.5	11	nC
Q_{gs}	Gate Source Charge			1.2		nC
Q_{gd}	Gate Drain Charge			2.1		nC
$t_{D(on)}$	Turn-On DelayTime	V_{GS}=-4.5V, V_{DS}=-10V, R_L=5Ω, R_{GEN}=6Ω		7.2		ns
t_r	Turn-On Rise Time			36		ns
$t_{D(off)}$	Turn-Off DelayTime			53		ns
t_f	Turn-Off Fall Time			56		ns
t_{rr}	Body Diode Reverse Recovery Time	I_F=-2A, dI/dt=100A/µs		37	49	ns
Q_{rr}	Body Diode Reverse Recovery Charge	I_F=-2A, dI/dt=100A/µs		27		nC

A: The value of $R_{\theta JA}$ is measured with the device mounted on 1in^2 FR-4 board with 2oz. Copper, in a still air environment with T_A =25°C. The value in any a given application depends on the user's specific board design. The current rating is based on the t≤ 10s thermal resistance rating.
B: Repetitive rating, pulse width limited by junction temperature.
C. The $R_{\theta JA}$ is the sum of the thermal impedence from junction to lead $R_{\theta JL}$ and lead to ambient.
D. The static characteristics in Figures 1 to 6 are obtained using 300 µs pulse width, duty cycle 0.5% max.
E. These tests are performed with the device mounted on 1 in^2 FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C. The SOA curve provides a single pulse rating.
Rev0: May 2008

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

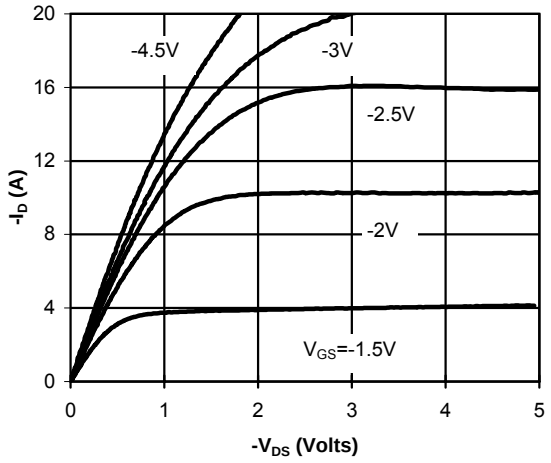

Fig 1: On-Region Characteristics

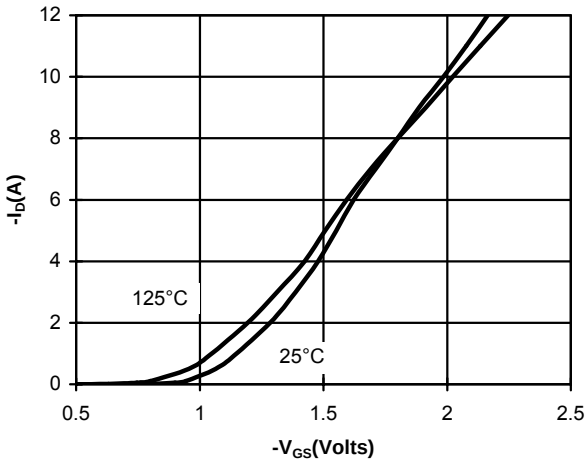

Figure 2: Transfer Characteristics

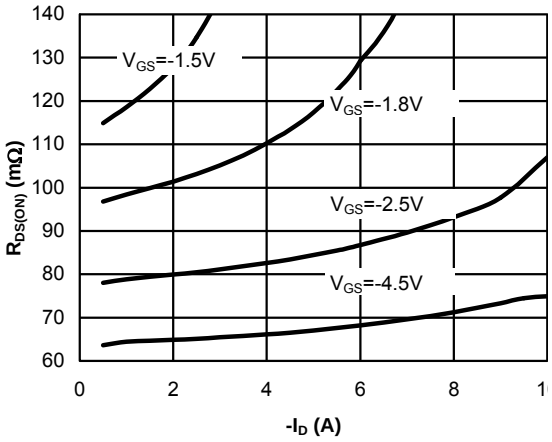

Figure 3: On-Resistance vs. Drain Current and Gate Voltage

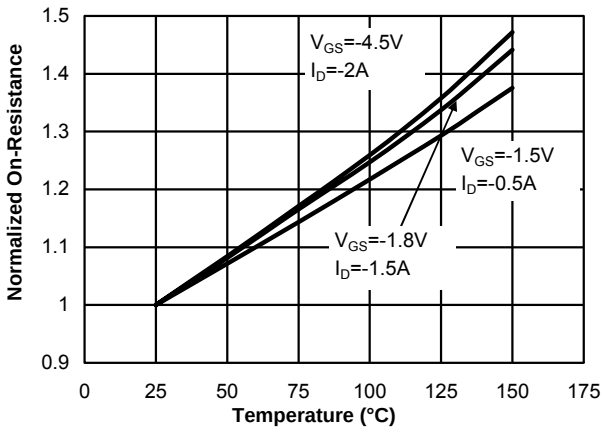

Figure 4: On-Resistance vs. Junction Temperature

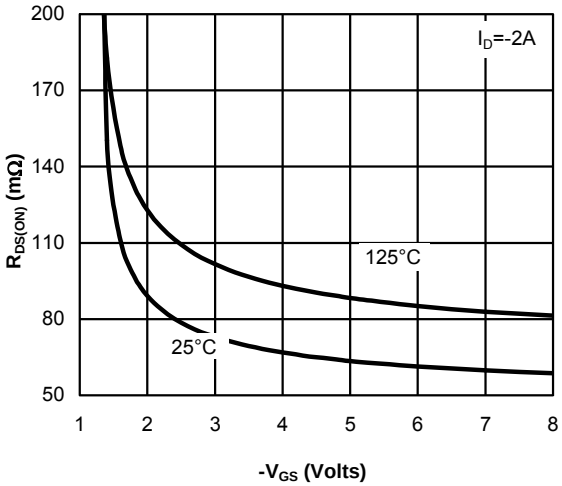

Figure 5: On-Resistance vs. Gate-Source Voltage

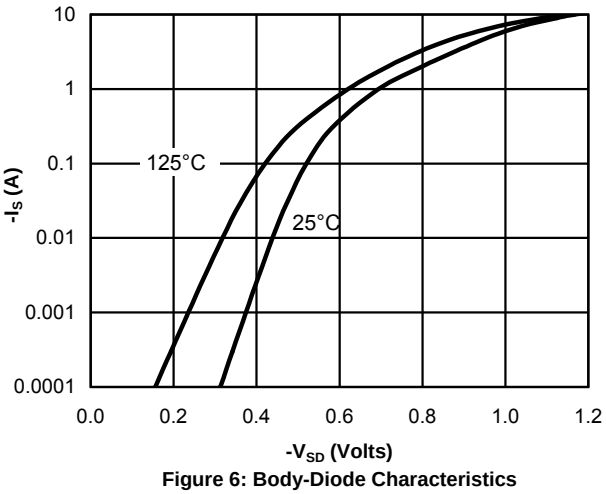

Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

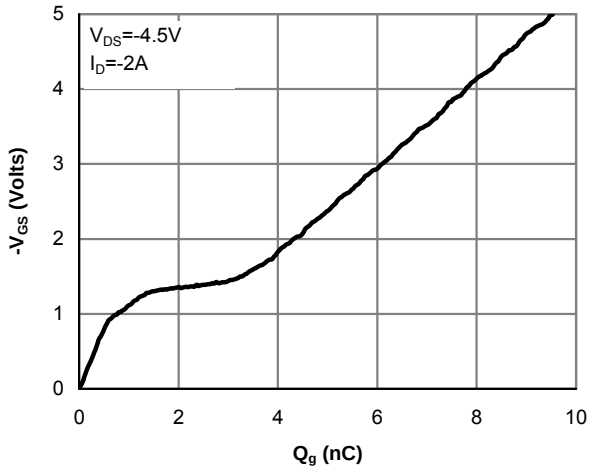

Figure 7: Gate-Charge Characteristics

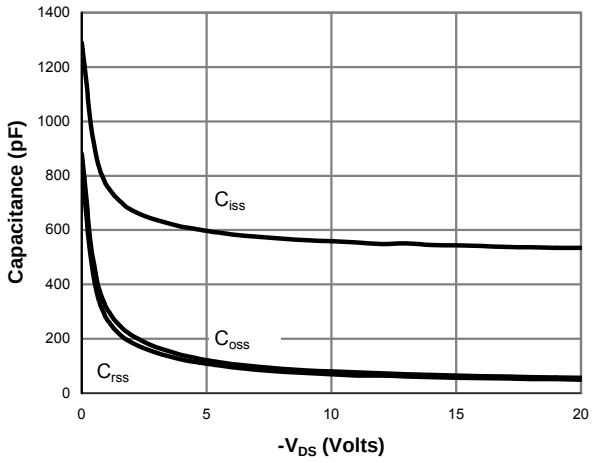

Figure 8: Capacitance Characteristics

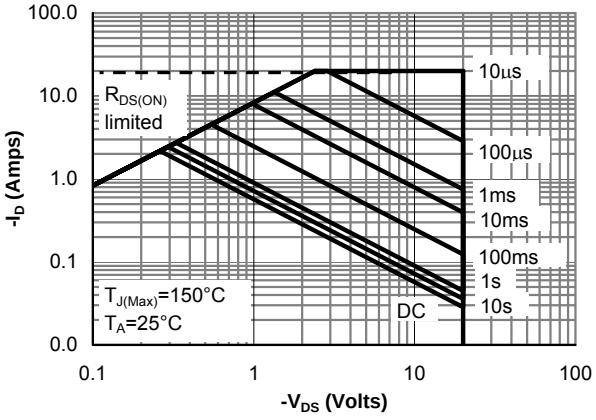

Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

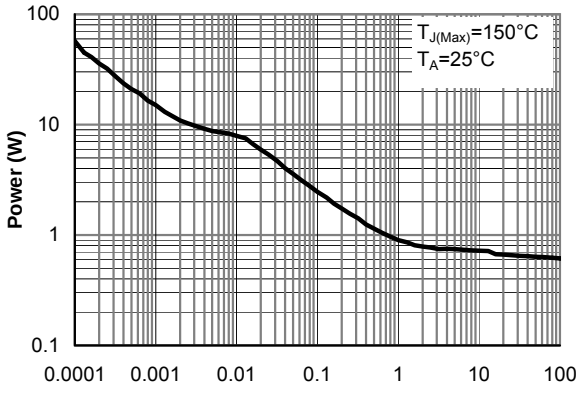

Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

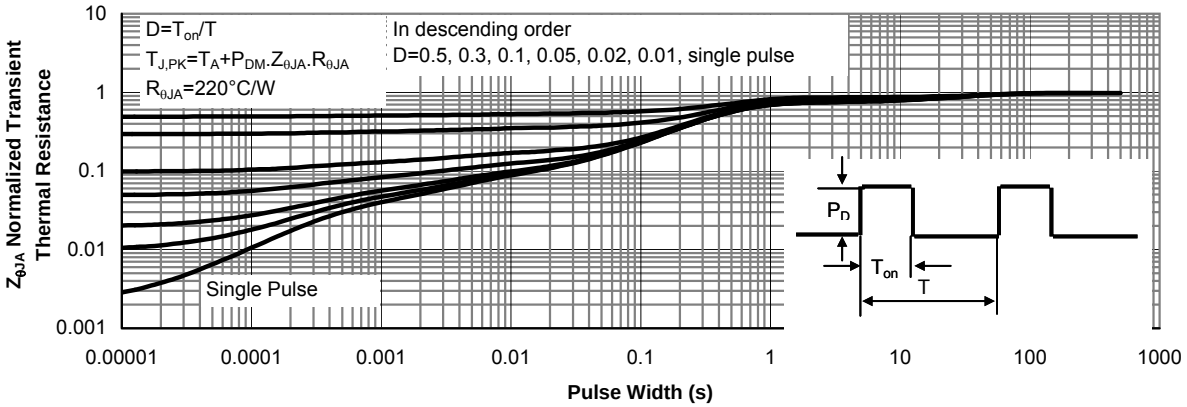

Figure 11: Normalized Maximum Transient Thermal Impedance